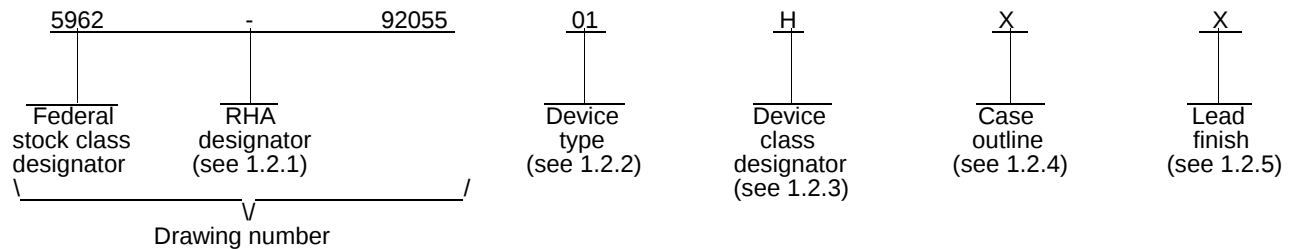


REVISIONS																			
LTR	DESCRIPTION										DATE (YR-MO-DA)					APPROVED			
A	Correct notes to tests in table I and figure 1. Update drawing requirements to MIL-PRF-38534.										01-06-14					Raymond Monnin			
REV																			
SHEET																			
REV																			
SHEET																			
REV STATUS					REV		A	A	A	A	A	A	A	A	A	A	A		
OF SHEETS					SHEET		1	2	3	4	5	6	7	8	9	10	11		
PMIC N/A					PREPARED BY Steve L. Duncan					DEFENSE SUPPLY CENTER COLUMBUS POST OFFICE BOX 3990 COLUMBUS, OHIO 43216-5000 http://www.dscc.dla.mil									
STANDARD MICROCIRCUIT DRAWING THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE AMSC N/A					CHECKED BY Michael C. Jones														
					APPROVED BY Kendall A. Cottongim					MICROCIRCUIT, HYBRID, LINEAR, 2-VOLT, DIRECT RESOLVER CONVERTER									
					DRAWING APPROVAL DATE 93-01-19														
										REVISION LEVEL A					SIZE A	CAGE CODE 67268	5962-92055		
										SHEET 1 OF 11									

1. SCOPE

1.1 Scope. This drawing documents five product assurance classes as defined in paragraph 1.2.3 and MIL-PRF-38534. A choice of case outlines and lead finishes which are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of radiation hardness assurance levels are reflected in the PIN.

1.2 PIN. The PIN shall be as shown in the following example:



1.2.1 Radiation hardness assurance (RHA) designator. RHA marked devices shall meet the MIL-PRF-38534 specified RHA levels and shall be marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.

1.2.2 Device type(s). The device type(s) identify the circuit function as follows:

Device type	Generic number	Circuit function	Frequency	Accuracy ± 1 LSB	BIT/VEL
01	SDC-14613II-112	14-bit, 2 V direct resolver converter	400 Hz	4 min	VEL
02	SDC-14613IIT-112	14-bit, 2 V direct resolver converter	400 Hz	4 min	BIT
03	SDC-14618II-112	16-bit, 2 V direct resolver converter	400 Hz	4 min	VEL
04	SDC-14618IIT-112	16-bit, 2 V direct resolver converter	400 Hz	4 min	BIT
05	SDC-14618II-114	16-bit, 2 V direct resolver converter	400 Hz	2 min	VEL
06	SDC-14618IIT-114	16-bit, 2 V direct resolver converter	400 Hz	2 min	BIT

1.2.3 Device class designator. This device class designator shall be a single letter identifying the product assurance level. All levels are defined by the requirements of MIL-PRF-38534 and require QML Certification as well as qualification (Class H, K, and E) or QML Listing (Class G and D). The product assurance levels are as follows:

Device class	Device performance documentation
K	Highest reliability class available. This level is intended for use in space applications.
H	Standard military quality class level. This level is intended for use in applications where non-space high reliability devices are required.
G	Reduced testing version of the standard military quality class. This level uses the Class H screening and In-Process Inspections with a possible limited temperature range, manufacturer specified incoming flow, and the manufacturer guarantees (but may not test) periodic and conformance inspections (Group A, B, C, and D).
E	Designates devices which are based upon one of the other classes (K, H, or G) with exception(s) taken to the requirements of that class. These exception(s) must be specified in the device acquisition document; therefore the acquisition document should be reviewed to ensure that the exception(s) taken will not adversely affect system performance.
D	Manufacturer specified quality class. Quality level is defined by the manufacturers internal, QML certified flow. This product may have a limited temperature range.

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1.2.4 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
X	See figure 1	36	Dual-in-line

1.2.5 Lead finish. The lead finish shall be as specified in MIL-PRF-38534.

1.3 Absolute maximum ratings. 1/

Positive supply voltage (V_{CC})	+7.0 V dc
Negative supply voltage (V_{EE})	-7.0 V dc
Reference input voltage	35 V rms
Digital input voltage range	-0.3 V dc to +7.0 V dc
Power dissipation, $T_A = +125^\circ\text{C}$ (P_D)	550 mW
Thermal resistance junction-to-case (θ_{JC})	8.0°C/W
Thermal resistance junction-to-ambient (θ_{JA})	20°C/W
Storage temperature range	-65°C to +150°C
Lead temperature (soldering, 10 seconds)	+300°C

1.4 Recommended operating conditions.

Positive supply voltage (V_{CC})	+4.75 V dc to +5.25 V dc
Negative supply voltage (V_{EE})	-4.75 V dc to -5.25 V dc
Reference input voltage range	2 V rms to 35 V rms
Reference input carrier frequency range	360 Hz to 5000 Hz
Signal input voltage range	1.70 V rms to 2.30 V rms
Ambient operating temperature range (T_A)	-55°C to +125°C

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.

SPECIFICATION

DEPARTMENT OF DEFENSE

MIL-PRF-38534 - Hybrid Microcircuits, General Specification for.

STANDARDS

DEPARTMENT OF DEFENSE

MIL-STD-883 - Test Method Standard Microcircuits.
MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

HANDBOOKS

DEPARTMENT OF DEFENSE

MIL-HDBK-103 - List of Standard Microcircuit Drawings.
MIL-HDBK-780 - Standard Microcircuit Drawings.

(Unless otherwise indicated, copies of the specification, standards, and handbooks are available from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

1/ Stresses above the absolute maximum ratings may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.

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3. REQUIREMENTS

3.1 Item requirements. The individual item performance requirements for device classes D, E, G, H, and K shall be in accordance with MIL-PRF-38534. Compliance with MIL-PRF-38534 may include the performance of all tests herein or as designated in the device manufacturer's Quality Management (QM) plan or as designated for the applicable device class. Therefore, the tests and inspections herein may not be performed for the applicable device class (see MIL-PRF-38534). Furthermore, the manufacturer may take exceptions or use alternate methods to the tests and inspections herein and not perform them. However, the performance requirements as defined in MIL-PRF-38534 shall be met for the applicable device class.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38534 and herein.

3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.4 herein and figure 1.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 2.

3.2.3 Block diagram. The block diagram shall be as specified on figure 3.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are defined in table I.

3.5 Marking of device(s). Marking of device(s) shall be in accordance with MIL-PRF-38534. The device shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's vendor similar PIN may also be marked in MIL-HDBK-103 and QML-38534.

3.6 Data. In addition to the general performance requirements of MIL-PRF-38534, the manufacturer of the device described herein shall maintain the electrical test data (variables format) from the initial quality conformance inspection group A lot sample, for each device type listed herein. Also, the data should include a summary of all parameters manually tested, and for those which, if any, are guaranteed. This data shall be maintained under document revision level control by the manufacturer and be made available to the preparing activity (DSCC-VA) upon request.

3.7 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to supply to this drawing. The certificate of compliance (original copy) submitted to DSCC-VA shall affirm that the manufacturer's product meets the performance requirements of MIL-PRF-38534 and herein.

3.8 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38534 shall be provided with each lot of microcircuits delivered to this drawing.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38534 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.

4.2 Screening. Screening shall be in accordance with MIL-PRF-38534. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DSCC-VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.

(2) T_A as specified in accordance with table I of method 1015 of MIL-STD-883.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T _A ≤ +125°C V _{CC} = +5 V dc, V _{EE} = -5 V dc unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Resolution <u>1/</u>	RES		7,8A,8B	01,02	14		Bits
				03-06	16		
Output accuracy <u>2/</u>	AOUT		7,8A,8B	01-04	-4	+4	LSB
				05,06	-7	+7	
Accuracy repeatability <u>2/ 3/</u>	AR		7,8A,8B	All	-1.0	+1.0	LSB
Reference input voltage range <u>3/</u>	V _{IN1}		4,5,6	All	2	35	V rms
Reference input impedance <u>3/</u>	Z _{IN1}	Single ended	4,5,6	All	60		kΩ
		Differential			120		
Reference input common mode range <u>3/</u>	V _{CM1}		4,5,6	All	-50	+50	V pk
Signal input impedance <u>3/</u>	Z _{IN2}	Line-to-ground	4,5,6	All	20		MΩ
Digital output low voltage <u>1/</u>	V _{OL}	I _{OL} = -1.6 mA	1,2,3	All		0.4	V
Digital output high voltage <u>1/</u>	V _{OH}	I _{OH} = 0.4 mA	1,2,3	All	2.8		V
Output leakage current <u>3/</u>	I _{OZ}		1,2,3	All	-60	+60	μA
Digital input high voltage <u>1/</u>	V _{IH}	Digital inputs $\overline{INH}$, $\overline{EL}$, and EM. V _{IN} = 2.0 V	1,2,3	All	pass/ fail		

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C ≤ T _A ≤ +125°C V _{CC} = +5 V dc, V _{EE} = -5 V dc unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Digital input low voltage <u>1/</u>	V _{IL}	Digital inputs $\overline{\text{INH}}$, $\overline{\text{EL}}$, and $\overline{\text{EM}}$. V _{IN} = 0.8 V	1,2,3	All		pass/ fail	
Digital input current <u>1/</u>	I _{IN}	Internal pull-up	4,5,6	All		-10	μA
Inhibit voltage <u>1/</u>	V _{INH}	No digital angles change while INH is logic 0 and analog input is rotating	7,8A,8B	All		0.8	V
Enable voltage <u>1/</u>	V _E	$\overline{\text{EM}}$ controls output bits 1 through 8 and EL controls output bits 9 through 14 for device types 01 and 02, and bits 9 through 16 for device types 03 through 06.	7,8A,8B	All		0.8	V
Disable voltage <u>1/</u> (high impedance)	V _D	$\overline{\text{EM}}$ controls output bits 1 through 8 and EL controls output bits 9 through 14 for device types 01 and 02, and bits 9 through 16 for device types 03 through 06.	7,8A,8B	All	2.0		V
Positive supply voltage	I _{CC}	V _{CC} = +5.25 V	1,2,3	All		+17	mA
Negative supply voltage	I _{EE}	V _{EE} = -5.25 V	1,2,3	All		-17	mA
Analog velocity output voltage	V _{OUT}	<u>4/</u>	7,8A,8B	All	3.24	4.00	V
Bandwidth <u>1/</u>	BW		7,8A,8B	All	72	134	Hz

- 1/ These parameters are tested on a go-no-go basis only or in conjunction with other measured parameters and are not directly testable.
- 2/ Output accuracy is measured at angles from 0°, to 180°, in 15° increments, and at 225°, 270°, and 315°.
- 3/ Parameters shall be tested as part of device initial characterization and after design and process changes. Parameter shall be guaranteed to the limits specified in table I for all lots not specifically tested.
- 4/ Analog output voltage is tested at 8 revolutions per second (rps) for device types 03 through 06 and at 2 rps for device types 01 and 02.

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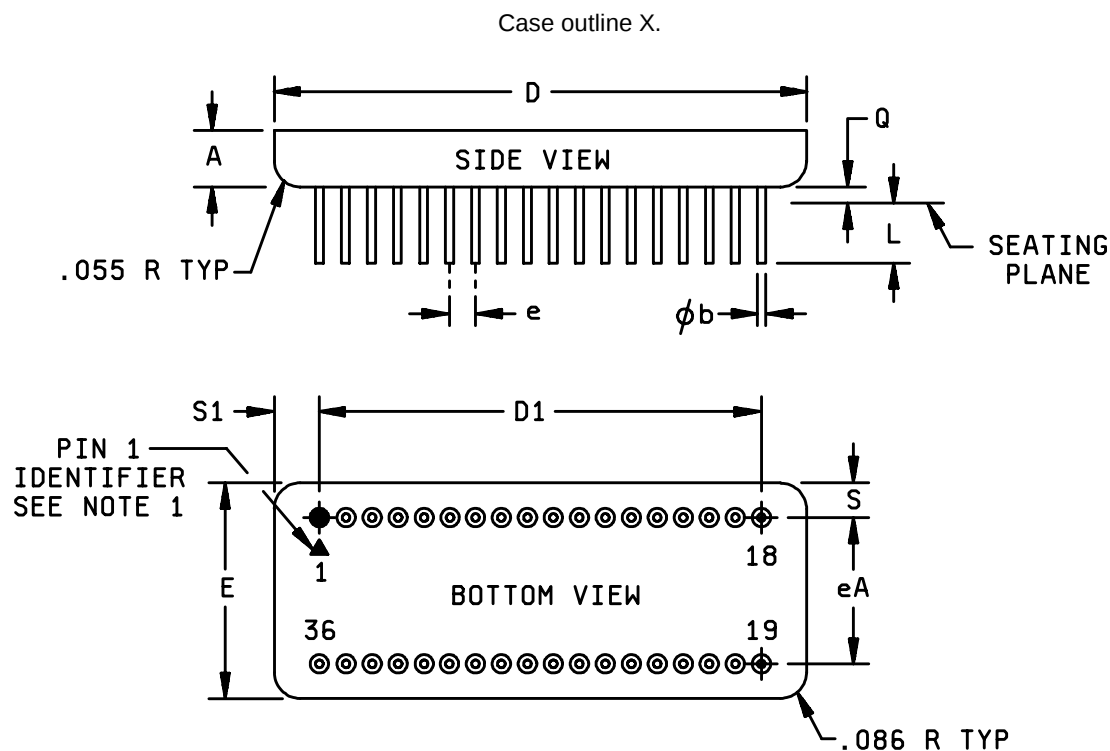
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Symbol	Millimeters		Inches	
	Minimum	Maximum	Minimum	Maximum
A	---	5.33	---	0.210
$\varnothing b$	0.46 TYP		0.018 TYP	
D	48.01	48.26	1.890	1.900
D1	43.05	43.31	1.695	1.705
E	19.56	19.81	0.770	0.780
e	2.54 TYP		0.100 TYP	
eA	15.11	15.37	0.595	0.605
L	5.84	---	0.230	---
Q	---	0.38	---	0.015
S	2.03	2.54	0.080	0.100
S1	2.29	2.79	0.090	0.110

NOTES:

1. Pin 1 is denoted by the contrasting colored bead and the ESD triangle on the under side.
2. Radius dimensions are in inches.
3. The U.S. government preferred system of measurement is the metric SI. This case outline was designed using inch-pound units of measurement. In case of problems involving conflicts between the metric and inch-pound units, the inch-pound units shall rule.
4. Pin number are for reference only.
5. Lead spacing dimensions apply only at seating plane.

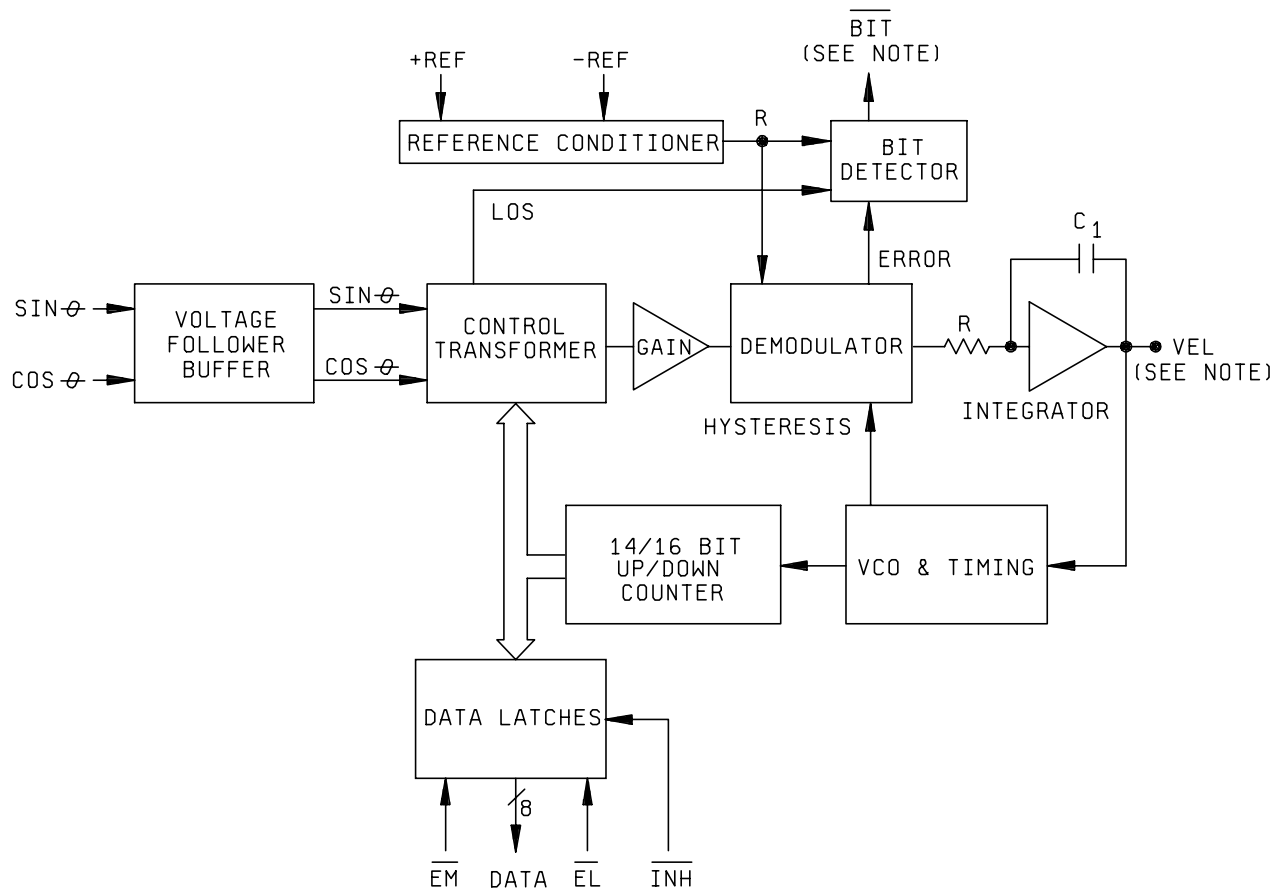
FIGURE 1. Case outline(s).

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Device types	01	02	03, 05	04, 06
Case outline	X	X	X	X
Terminal number	Terminal symbol	Terminal symbol	Terminal symbol	Terminal symbol
1	No connection	No connection	No connection	No connection
2	+COS A	+COS A	+COS A	+COS A
3	+SIN A	+SIN A	+SIN A	+SIN A
4	No connection	No connection	No connection	No connection
5	GND	GND	GND	GND
6	A GND	A GND	A GND	A GND
7	No connection	No connection	No connection	No connection
8	+COS B	+COS B	+COS B	+COS B
9	+SIN B	+SIN B	+SIN B	+SIN B
10	No connection	No connection	No connection	No connection
11	V _{EE} (-5 V supply)	V _{EE} (-5 V supply)	V _{EE} (-5 V supply)	V _{EE} (-5 V supply)
12	V _{CC} (+5 V supply)	V _{CC} (+5 V supply)	V _{CC} (+5 V supply)	V _{CC} (+5 V supply)
13	No connection	No connection	No connection	No connection
14	+COS C	+COS C	+COS C	+COS C
15	+SIN C	+SIN C	+SIN C	+SIN C
16	No connection	No connection	No connection	No connection
17	-REF	-REF	-REF	-REF
18	+REF	+REF	+REF	+REF
19	<u>EM</u> C	<u>EM</u> C	<u>EM</u> C	<u>EM</u> C
20	<u>EL</u> C	<u>EL</u> C	<u>EL</u> C	<u>EL</u> C
21	VEL C	BIT C	VEL C	BIT C
22	Bit 1/9	Bit 1/9	Bit 1/9	Bit 1/9
23	Bit 2/10	Bit 2/10	Bit 2/10	Bit 2/10
24	Bit 3/11	Bit 3/11	Bit 3/11	Bit 3/11
25	Bit 4/12	Bit 4/12	Bit 4/12	Bit 4/12
26	Bit 5/13	Bit 5/13	Bit 5/13	Bit 5/13
27	Bit 6/14	Bit 6/14	Bit 6/14	Bit 6/14
28	Bit 7	Bit 7	Bit 7/15	Bit 7/15
29	<u>Bit</u> 8	<u>Bit</u> 8	<u>Bit</u> 8/16	<u>Bit</u> 8/16
30	<u>EL</u> B	<u>EL</u> B	<u>EL</u> B	<u>EL</u> B
31	EM B	<u>EM</u> B	EM B	<u>EM</u> B
32	<u>VEL</u> B	<u>BIT</u> B	<u>VEL</u> B	<u>BIT</u> B
33	<u>INH</u> (inhibit)	<u>INH</u> (inhibit)	<u>INH</u> (inhibit)	<u>INH</u> (inhibit)
34	<u>EL</u> A	<u>EL</u> A	<u>EL</u> A	<u>EL</u> A
35	EM A	<u>EM</u> A	EM A	<u>EM</u> A
36	VEL A	BIT A	VEL A	BIT A

FIGURE 2. Terminal connections.

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NOTE: __

1. BIT is not connected on device types 01, 03, and 05. VEL is not connected on device types 02, 04, and 06.

FIGURE 3. Block diagram.

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TABLE II. Electrical test requirements.

MIL-PRF-38534 test requirements	Subgroups (in accordance with MIL-PRF-38534, group A test table)
Interim electrical parameters	1,4,7
Final electrical parameters	1*,2,3,4,5,6,7,8A,8B
Group A test requirements	1,2,3,4,5,6,7,8A,8B
Group C end-point electrical parameters	1,2,3,4,5,6,7,8A,8B
End-point electrical parameters for radiation hardness assurance (RHA) devices	Not applicable

* PDA applies to subgroup 1.

4.3 Conformance and periodic inspections. Conformance inspection (CI) and periodic inspection (PI) shall be in accordance with MIL-PRF-38534 and as specified herein.

4.3.1 Group A inspection (CI). Group A inspection shall be in accordance with MIL-PRF-38534 and as follows:

- a. Tests shall be as specified in table II herein.
- b. Subgroups 9, 10, and 11 shall be omitted.

4.3.2 Group B inspection (PI). Group B inspection shall be in accordance with MIL-PRF-38534.

4.3.3 Group C inspection (PI). Group C inspection shall be in accordance with MIL-PRF-38534 and as follows:

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DSCC-VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
 - (2) T_A as specified in accordance with table I of method 1005 of MIL-STD-883.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.3.4 Group D inspection (PI). Group D inspection shall be in accordance with MIL-PRF-38534.

4.3.5 Radiation Hardness Assurance (RHA) inspection. RHA inspection is not currently applicable to this drawing.

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5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38534.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-PRF-38534.

6.4 Record of users. Military and industrial users shall inform Defense Supply Center Columbus when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0544.

6.5 Comments. Comments on this drawing should be directed to DSCC-VA, Post Office Box 3990, Columbus, Ohio 43216-5000, or telephone (614) 692-0512.

6.6 Sources of supply. Sources of supply are listed in MIL-HDBK-103 and QML-38534. The vendors listed in MIL-HDBK-103 and QML-38534 have submitted a certificate of compliance (see 3.7 herein) to DSCC-VA and have agreed to this drawing.

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STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 01-06-14

Approved sources of supply for SMD 5962-92055 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38534 during the next revisions. MIL-HDBK-103 and QML-38534 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This bulletin is superseded by the next dated revisions of MIL-HDBK-103 and QML-38534.

Standard microcircuit drawing PIN <u>1</u> /	Vendor CAGE number	Vendor similar PIN <u>2</u> /
5962-9205501HXA 5962-9205501HXA 5962-9205501HXA 5962-9205501HXA 5962-9205501HXC 5962-9205501HXC 5962-9205501HXC 5962-9205501HXC	S7631 19645 S7631 19645 S7631 19645 S7631 19645	SDC-14613II-152 SDC-14613II-152 SDC-14613II-142 SDC-14613II-142 SDC-14613II-132 SDC-14613II-132 SDC-14613II-112 SDC-14613II-112
5962-9205502HXA 5962-9205502HXA 5962-9205502HXA 5962-9205502HXA 5962-9205502HXC 5962-9205502HXC 5962-9205502HXC 5962-9205502HXC	S7631 19645 S7631 19645 S7631 19645 S7631 19645	SDC-14613IIT-152 SDC-14613IIT-152 SDC-14613IIT-142 SDC-14613IIT-142 SDC-14613IIT-132 SDC-14613IIT-132 SDC-14613IIT-112 SDC-14613IIT-112
5962-9205503HXA 5962-9205503HXA 5962-9205503HXA 5962-9205503HXA 5962-9205503HXC 5962-9205503HXC 5962-9205503HXC 5962-9205503HXC	S7631 19645 S7631 19645 S7631 19645 S7631 19645	SDC-14618II-152 SDC-14618II-152 SDC-14618II-142 SDC-14618II-142 SDC-14618II-132 SDC-14618II-132 SDC-14618II-112 SDC-14618II-112
5962-9205504HXA 5962-9205504HXA 5962-9205504HXA 5962-9205504HXA 5962-9205504HXC 5962-9205504HXC 5962-9205504HXC 5962-9205504HXC	S7631 19645 S7631 19645 S7631 19645 S7631 19645	SDC-14618IIT-152 SDC-14618IIT-152 SDC-14618IIT-142 SDC-14618IIT-142 SDC-14618IIT-132 SDC-14618IIT-132 SDC-14618IIT-112 SDC-14618IIT-112
5962-9205505HXA 5962-9205505HXA 5962-9205505HXA 5962-9205505HXA 5962-9205505HXC 5962-9205505HXC 5962-9205505HXC 5962-9205505HXC	S7631 19645 S7631 19645 S7631 19645 S7631 19645	SDC-14618II-154 SDC-14618II-154 SDC-14618II-144 SDC-14618II-144 SDC-14618II-134 SDC-14618II-134 SDC-14618II-114 SDC-14618II-114

See footnotes at end of table.

STANDARD MICROCIRCUIT DRAWING BULLETIN - Continued.

DATE: 01-06-14

Standard microcircuit drawing PIN <u>1</u> /	Vendor CAGE number	Vendor similar PIN <u>2</u> /
5962-9205506HXA	S7631	SDC-14618IIT-154
5962-9205506HXA	19645	SDC-14618IIT-154
5962-9205506HXA	S7631	SDC-14618IIT-144
5962-9205506HXA	19645	SDC-14618IIT-144
5962-9205506HXC	S7631	SDC-14618IIT-134
5962-9205506HXC	19645	SDC-14618IIT-134
5962-9205506HXC	S7631	SDC-14618IIT-114
5962-9205506HXC	19645	SDC-14618IIT-114

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the Vendor to determine its availability.
- 2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE
numberVendor name
and address

S7631

DDC Ireland, LTD.
Cork Business & Technology Park
Model Farm Road
Cork, Ireland

19645

Data Device Corporation
105 Wilbur Place
Bohemia, NY 11716-2482

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